## Notic of R ferences Cited

Application/Control N 09/844,481	- R examinati	Applicant(s)/Patent Under R examination ONISHI ET AL.		
Examiner	Art Unit			
   Matthew Landau	2815	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,754,310	06-1988	Coe, David J.	257/287
	В	US-6,097,063	08-2000	Fujihira, Tatsuhiko	257/139
	С	US-5,710,455	01-1998	Bhatnagar et al.	257/472
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ŀ	US-			
	j	US-			
	κ	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 200169682 A2	09-2001	World Intellect	AHLERS et al.	H01L 29/00
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

	TOW A LET DOOMETTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	w				
	x				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.